Home	Loca	tion	Years	Diamond	Scans	Si	ngle Runs		s so	scCVD		D S	Silicon Amp		plifier Boar		Boards	
Run Plan Overview for the Test Campaign in August 2017-2																		
D D]	Di si ti sas	Amplifier	Sub Plan	Run Type	Runs	Events	Front					Middle			Back			
KUN PLAN	Digitiser						Info	Diamond	Detector	Bias [V]	Info	Diamond	Detector	Bias [V]	Info	Diamond	Detector	Bias [V]
01	ROC	ROC	1	angle scan	001 - 011	2.9M	Runs	<u>II6-B6</u>	3D-pixel	-50	Runs	<u>II6-A2</u>	3D-pixel	-50	Runs	<u>Si352</u>	pixel	-150
02	DRS4	OSU1	2	rate scan	019 - 040	7.5M	Runs	Runs <u>II6-B2</u>	pad	-1000				Runs			-1000	
			2.1	up scan	029 - 035	2.0M	Runs					-				<u> 116-97</u>		pad
			2.2	rate scan	024 - 040	5.5M	Runs											
03	DRS4	0SU1	3	rate scan	042 - 065	8.2M	<u>Runs</u>	<u>II6-B2</u>	pad		-			Runs				
			3.1	up scan	053 - 059	2.4M	<u>Runs</u>			+1000				Runs	<u>II6-97</u>	pad	+1000	
			3.2	rate scan	042 - 053	4.1M	<u>Runs</u>								Runs			
04	DRS4	0SU1	4	rate scan	087 - 097	1.8M	<u>Runs</u>	SiD2	pad	+150	_			Runs	S129	pad	-500	
			4.1	up scan	087 - 092	1.0M	<u>Runs</u>	3002		1130	-				Runs	. 3123	pad	- 300
05	CAEN	0SU1	5	rate scan	155 - 164	1.5M	Runs	SiD2	pad	+150		-			Runs	<u>5129</u>	pad	-500
06	OSCI	OSU1	6	rate scan	170 - 176	?	<u>Runs</u>	SiD2	pad	+150		-			Runs	<u>5129</u>	pad	-500
07	DRS4	C6_1, Cx_2	7	voltage scan	179 - 187	7.0M	<u>Runs</u>	SiD6	pad	- 500		-			Runs	<u>II6-A7</u>	3D-multi	-30100
08	DRS4	Cx_2, C6_1	8	digitiser test	188 - 202	6.0M	<u>Runs</u>	SiD6	pad	-500		-			Runs	<u>II6-A7</u>	3D-multi	+100 → -100
09	DRS4	Cx_2, C6_2	9	rate scan	265 - 271	1.9M	Runs	<u>L100</u>	pad	+1000		-			Runs	<u>CMS04</u>	pad	+350
10	DRS4	C6_1, C6_2	10	rate scan	274 - 280	2.0M	Runs	<u>L100</u>	pad	-1000		-			Runs	<u>CMS04</u>	pad	-800
11	DRS4	Cx_2, C6_2	11	digitiser test	281 - 281	0.6M	Runs	<u>L100</u>	pad	-1000		-			Runs	<u>CMS04</u>	pad	-800
12	DRS4	C6_2, Cx_2	12	digitiser test	282 - 282	0.6M	Runs	<u>L100</u>	pad	-1000		-			Runs	<u>CMS04</u>	pad	-800